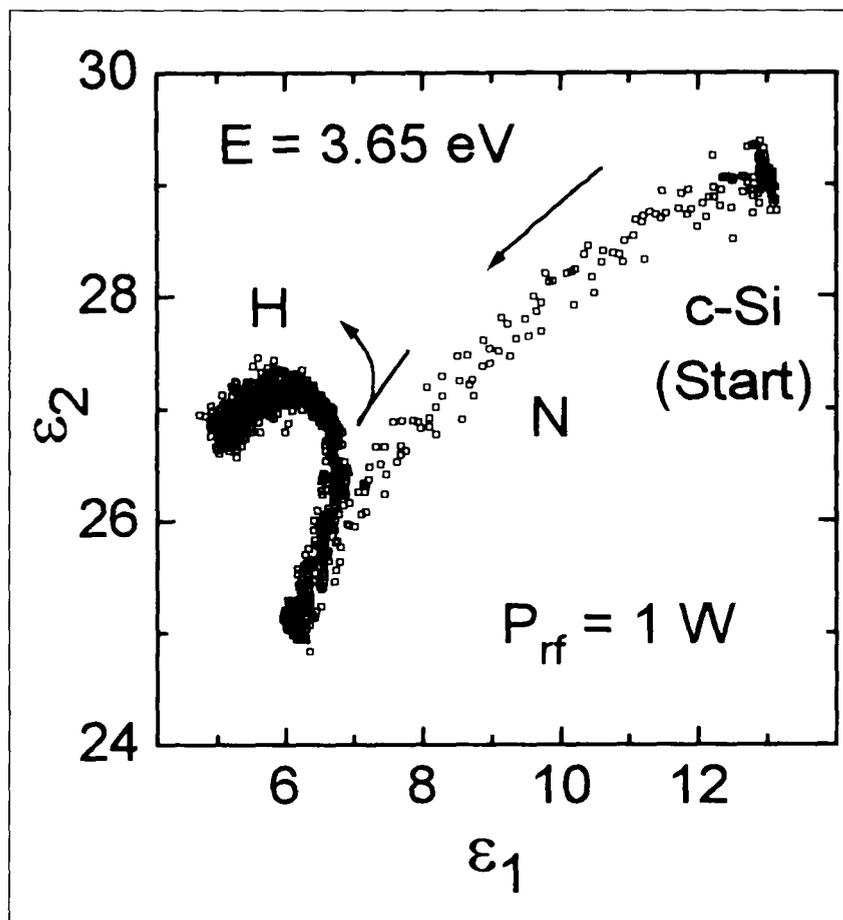


Figures appearing in the EDITOR'S CHOICE are those arising from materials research which strike the editor's fancy as being aesthetically appealing and eye-catching. No further criteria are applied and none should be assumed. When taken out of context, such figures often evoke images beyond and unrelated to the original meaning. Submissions of candidate figures are welcome and should include a complete source citation, a photocopy of the report in which it appears (or will appear), and a reproduction-quality original drawing or photograph of the figure in question.



History repeats itself and so does EDITOR'S CHOICE. This month's figure, which presents data gathered by kinetic ellipsometry on amorphous hydrogenated silicon during film deposition, is the second such figure to appear in this department of the *MRS Bulletin*. Avid readers will recall that the inaugural EDITOR'S CHOICE, which appeared in the January/February 1986 issue (Vol. XI, No. 1, p. 10), showed the (ϵ_1, ϵ_2) pair of effective optical indices evolve in a spiral trajectory from initial substrate value to the thick-film limit. The issue's example, on the other hand, shows a bouncing ball trajectory in going from the crystalline silicon substrate to the optically thick film. One might have at first mistaken the pattern as a calligrapher's version of the common check mark. However, the arrows clearly show the long stroke was made first, and we have taken the position that no one checks that way. To check our position and see further experimental details, you can consult "In-Situ Ellipsometric Study of the Dependence of a-Si:H Film Growth on Substrate Properties and Ignition Procedures" by U.I. Schmidt, W. Herbst, B. Schröder, and H. Oechsner in *Amorphous Silicon Technology-1994*, edited by E.A. Schiff, M. Hack, A. Madan, M. Powell, and A. Matsuda (MRS Symposium Proceedings, Vol. 336, Pittsburgh, PA, 1994) p. 85-90.

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